

NISTTech

A Stroboscopic Transmission Electron Microscope (TEM) for Imaging at MHz and GHz Rates

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Abstract

Researchers at NIST and at the Colorado School of Mines have invented a new atom probe tomography instrument that incorporates an extreme-UV (XUV) laser and in situ electron-beam imaging of the specimen. The present invention provides a new metrology tool to resolve challenges in fabricating novel materials in complex three dimensional structures.

Status of Availability

This invention is available for licensing exclusively or non-exclusively in any field of use.

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